
ZSFP+ 0.8 mm, 25 Gb/s SMT PT Connector

1. SCOPE

1.1. Content

This specification covers performance, tests and quality requirements for the TE Connectivity (TE) Small Form Factor Pluggable (SFP) 0.8 mm, 25 Gb/s SMT PT Connector.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

1.3. Qualification testing on the subject product line plan to complete on 17DecNov12. The Qualification Test Report number for this testing is 501-128004.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. TE Documents

- 114-13120: Application Specification (Small Form Factor Pluggable (SFP) and SFP+ Surface Mount PT Connectors and Cage Assemblies)
- 501-128004: Qualification Test Report (SFP 0.8 mm, 25 Gb/s Fiber Channel PT Connector)

2.2. Industry Documents

- EIA-364: Electrical Connector/Socket Test Procedures Including Environmental Classifications
- IPC/ECA J-STD-002C: Solderability Tests for Component Leads, Terminations, Lugs, Terminals and Wires

2.3. Reference Document

109-197: Test Specification (TE Test Specifications vs EIA and IEC Test Methods)

3. REQUIREMENTS

3.1. Design and Construction

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2. Material

Materials used in the construction of this product shall be as specified on the applicable product drawing

3.3. Ratings

- Voltage: 120 volts AC
- Current: 0.5 ampere maximum per contact
- Temperature: -55 to 85°C
- Differential Impedance: 100 ± 10 ohms, 35 psec t_r (20 to 80%)

3.4. Performance and Test Description

Product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

3.5. Test Requirements and Procedures Summary

Test Description	Requirement	Procedure
Initial examination of product.	Meets requirements of product drawing and Application Specification 114-13120.	EIA-364-18. Visual and dimensional (C of C) inspection per product drawing.
Final examination of product.	Meets visual requirements.	EIA-364-18. Visual inspection.
ELECTRICAL		
Low Level Contact Resistance (LLCR).	ΔR 10 milliohms maximum for signal contacts.	EIA-364-23. Subject specimens to 100 milliamperes maximum and 20 millivolts DC maximum open circuit voltage.
Insulation resistance.	1000 megohms minimum.	EIA-364-21. 100 volts DC, 2 minute hold. Test between adjacent contacts of unmated, board mounted specimens.
Withstanding voltage.	One minute hold with no breakdown or flashover.	EIA-364-20, Condition I. 300 volts AC at sea level. Test between adjacent contacts, signal to signal and signal to ground as applicable.
MECHANICAL		
Connector solderability.	Solderable area shall have a minimum of 95% solder coverage.	IPC/ECA J-STD-002C, Test S1. Subject specimens to solderability.
Random vibration.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA-364-28, Test Condition VII, Level D. Subject mated specimens to 3.10 G's rms between 20 to 500 Hz. Fifteen minutes in each of 3 mutually perpendicular planes.

Figure 1 (continued)

Test Description	Requirement	Procedure
Mechanical shock.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA-364-27, Method H. Subject mated specimens to 30 G's half-sine shock pulses of 11 milliseconds duration. Three shocks in each direction applied along 3 mutually perpendicular planes, 18 total shocks.
Durability.	See Note.	EIA-364-9. Mate and unmate specimens with cage latches engaged for 100 cycles at a maximum rate of 500 cycles per hour.
ENVIRONMENTAL		
Thermal shock.	See Note.	EIA-364-32, Test Condition VII. Subject mated specimens to 10 cycles between -55 and 85°C with 30 minute dwells at temperature extremes and 1 minute transition between temperatures.
Humidity/temperature cycling.	See Note.	EIA-364-31, Method III. Subject mated specimens to 10 cycles (10 days) between 25 and 65°C at 80 to 100% RH.
Temperature life, preconditioning.	See Note.	EIA-364-17, Method A. Subject mated specimens to 105°C for 72 hours.
Temperature life.	See Note.	EIA-364-17, Method A, Test Condition 4. Subject mated specimens to 105°C for 120 hours.
Mixed flowing gas.	See Note.	EIA-364-65, Class IIA (4 gas). Subject board mounted specimens to environmental Class IIA for 14 days. One-half of the specimens (receptacle only) unmated for 7 days followed by 7 days mated. The remaining one-half of the specimens mated for 14 days.
Thermal disturbance.	See Note.	Subject mated and board mounted specimens to 10 temperature cycles between $15 \pm 3^\circ\text{C}$ and $85 \pm 3^\circ\text{C}$ as measured on the part. Ramp times shall be a minimum of 2°C per minute with dwell times long enough to ensure contacts reach the temperature extremes (30 minutes). Humidity not controlled.

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

Figure 1 (end)

3.6. Product Qualification and Requalification Test Sequence

Test or Examination	Test Group (a)				
	1	2	3	4	5
	Test Sequence (b)				
Initial examination of product	1	1	1	1	1
LLCR	2,6	2,4,6	2,5,7		
Insulation resistance				2,6	
Withstanding voltage				3,7	
Connector solderability					2
Random vibration	4				
Mechanical shock	5				
Durability	3(c)				
Thermal shock				4(d)	
Humidity/temperature cycling		5		5	
Temperature life, preconditioning			3(d)		
Temperature life		3(d)			
Mixed flowing gas			4		
Thermal disturbance			6		
Final examination of product	7	7	8	8	3

- (a) See paragraph 4.1.A.
(b) Numbers indicate sequence in which tests are performed.
(c) Latches engaged.
(d) Precondition specimens with 20 durability cycles with latches engaged.

Figure 2

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Testing

A. Specimen Selection

Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Test group 1 shall consist of 5 specimens of each plating type, PdNi and Au. Test groups 2 and 4 shall consist of 5 specimens with PdNi plating. Test group 3 shall consist of 10 specimens of each plating type, PdNi and Au. Test group 5 shall consist of 5 specimens with Au plating.

A specimen shall consist of a connector with cage.

B. Test Sequence

Qualification inspection shall be verified by testing specimens as specified in Figure 2.

4.2. Requalification Testing

If changes significantly affecting form, fit or function are made to the product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/product, quality and reliability engineering.

4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify the product. If product failure occurs, corrective action shall be taken and specimens resubmitted for qualification. Testing to confirm corrective action is required before resubmitted.

4.4. Quality Conformance Inspection

The applicable quality inspection plan shall specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

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